

0.6um CMOS and BiCMOS Vanguard Qualification Summary

0.6UM CMOS LTC3612			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	2 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	3 x 45	Pass
Early Life Failure Rate (ELFR)	AEC Q100-008	3 x 800	Pass

0.6UM CMOS LTC3615			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	3 x 45	Pass
Early Life Failure Rate (ELFR)	AEC Q100-008	3 x 800	Pass

0.6UM CMOS LTC2977			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	1 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	1 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	1 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	1 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	1 x 77	Pass

0.6UM BiCMOS LTC3850			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	3 x 45	Pass
Early Life Failure Rate (ELFR)	AEC Q100-008	3 x 800	Pass

0.6UM BICMOS LTC4270			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	3 x 45	Pass
Early Life Failure Rate (ELFR)	AEC Q100-008	3 x 800	Pass

0.6UM BICMOS LTC3112			
TEST	SPECIFICATION	SAMPLE SIZE (LOTS X SAMPLE)	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	3 x 45	Pass
Early Life Failure Rate (ELFR)	AEC Q100-008	3 x 800	Pass